

Notice of References Cited	Application/Control No. 10/822,858		Applicant(s)/Patent Under Reexamination SANGWAN ET AL.	
	Examiner Christopher R. Tate		Art Unit 1655	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0096524	05-2004	Nair et al.	424/725
*	B	US-2004/0258781	12-2004	Nair et al.	424/769
*	C	US-2004/0033273	02-2004	Patwardhan et al.	424/725
*	D	US-6,866,872	03-2005	Tomi et al.	424/725
*	E	US-6,713,092	03-2004	Ghosal, Shibnath	424/725
*	F	US-6,153,198	11-2000	Ghosal, Shibnath	424/773
*	G	US-5,494,668	02-1996	Patwardhan, Bhushan	424/756
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002187846	07-2002	Japan	Kameyama et al-JPAB Abstr	----
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Dinan et al. J. Chromatogr. A. 2001. Vol. 935, pages 105-123.			
	V	Kaufmann et al. Chromatographia. 2001. Vol. 54, pages 394-398.			
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.